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## APPLICANTS

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\*\* CONTINUING DATA \*\*\*\*\*

None/V.N

\*\* FOREIGN APPLICATIONS \*\*\*\*\*

Yes/V.N

JAPAN 2002-203158 07/11/2002

IF REQUIRED, FOREIGN FILING LICENSE GRANTED

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Foreign Priority claimed 35 USC 119 (a-d) conditions met Verified and Acknowledged	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance <u>V. Nguyen</u> Examiner's Signature Initials	STATE OR  COUNTRY JAPAN	SHEETS  DRAWING 25	TOTAL  CLAIMS 33	INDEPENDENT  CLAIMS 2
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## TITLE

Semiconductor testing apparatus and semiconductor testing method

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